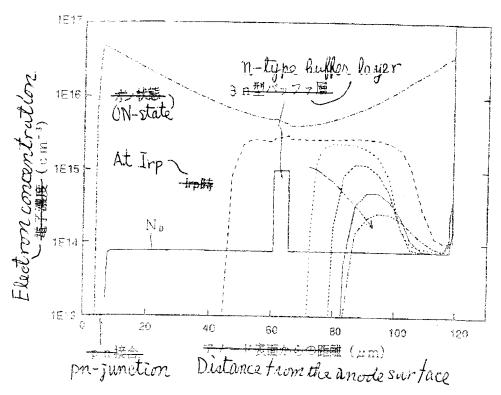
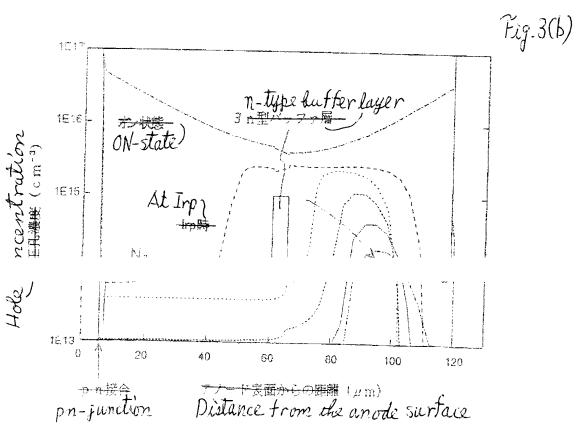
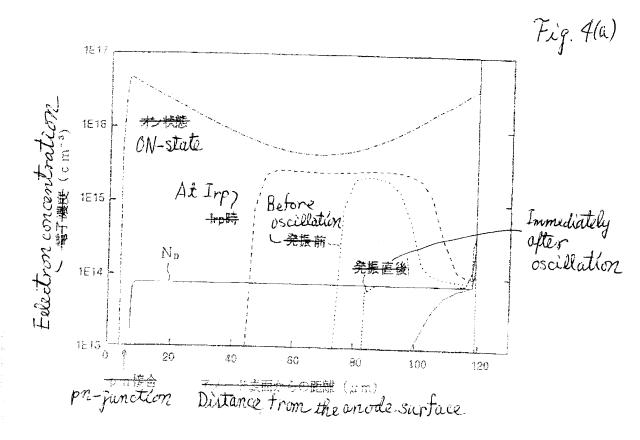
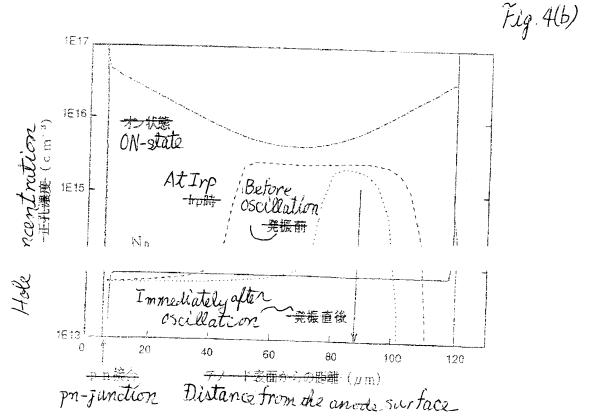


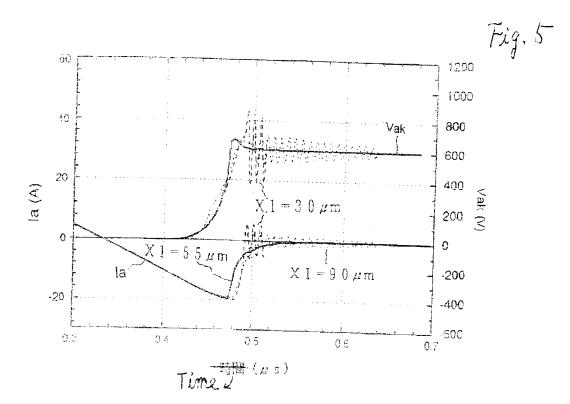
Fig. 3(a)

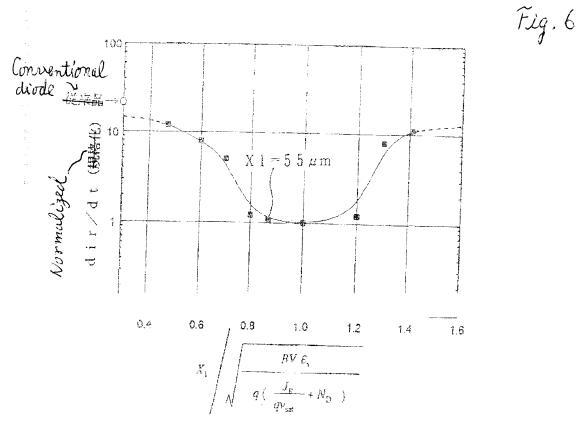




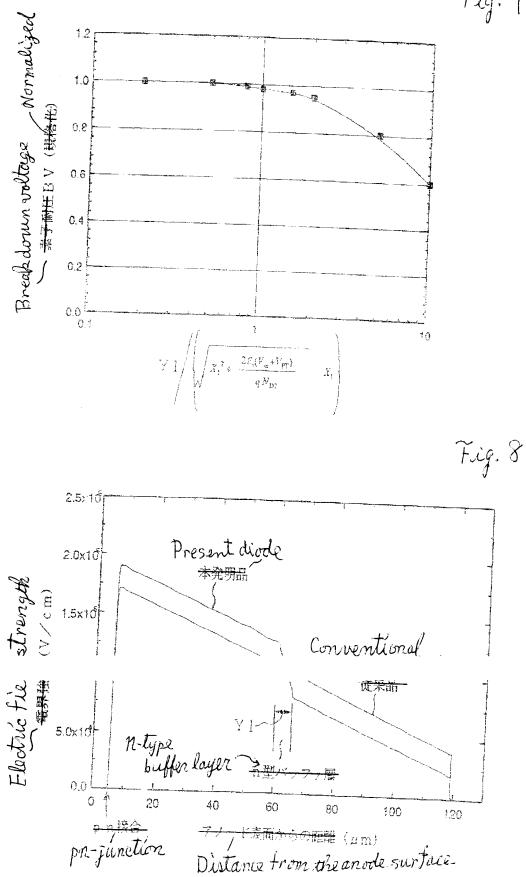












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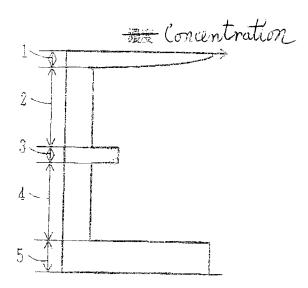
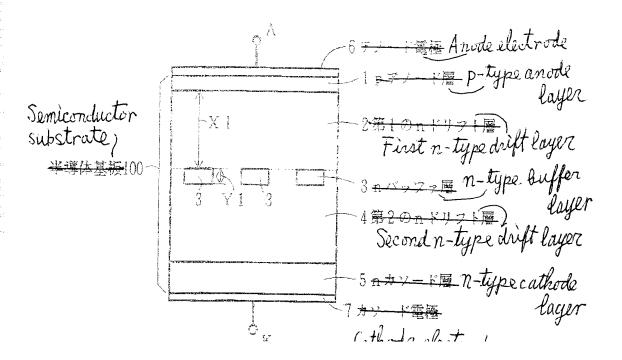
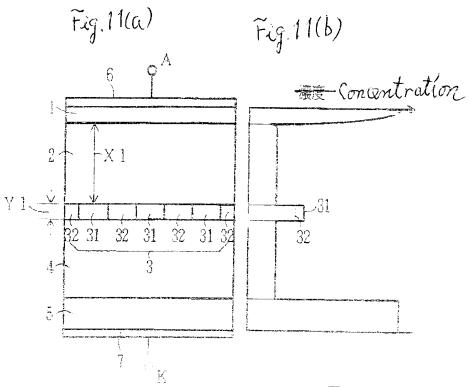


Fig. 10





事態 First n-type duffer negion (Hearily doped)
Second n-type buffer region (Lightly doped)

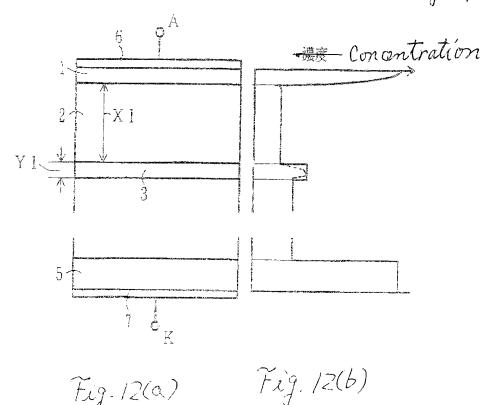
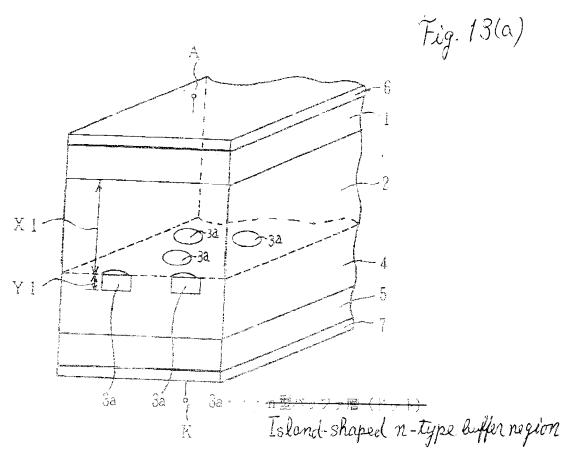


Fig. 12(a)



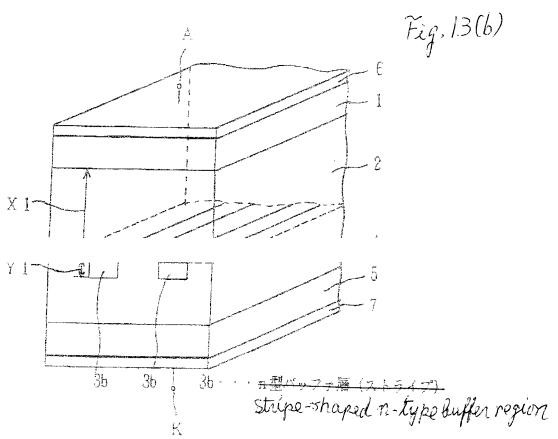
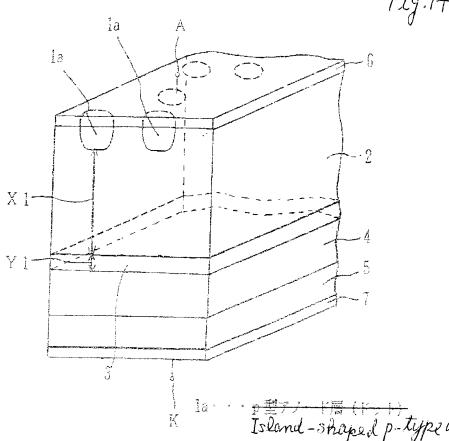
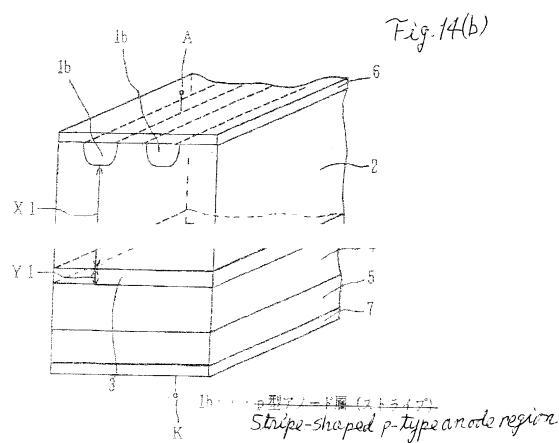
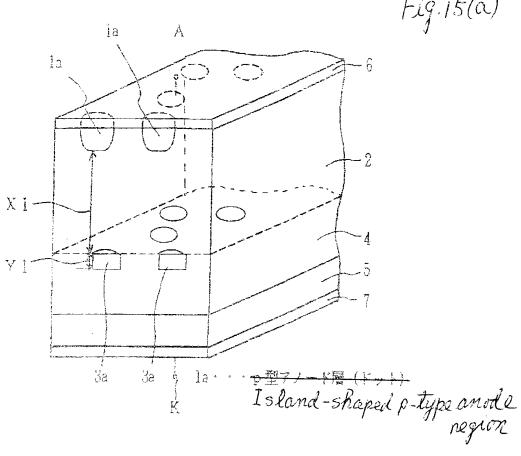


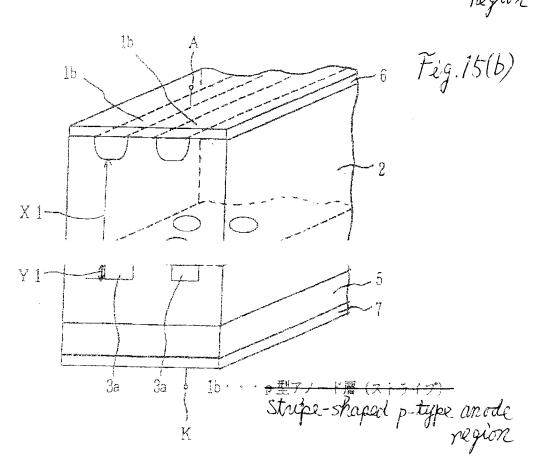
Fig. 14(a)

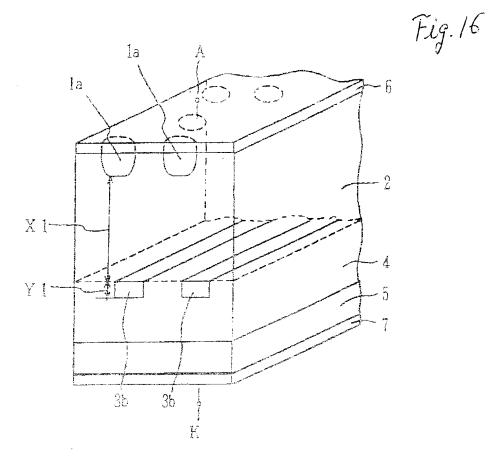


p型アノード層(ドート) Island-shaped p-type anode region

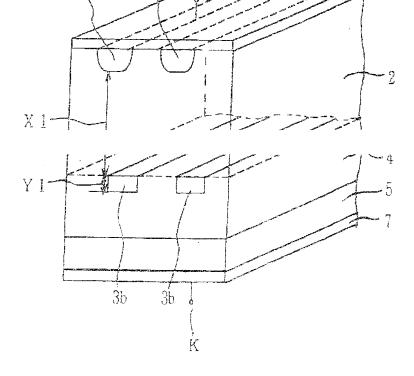








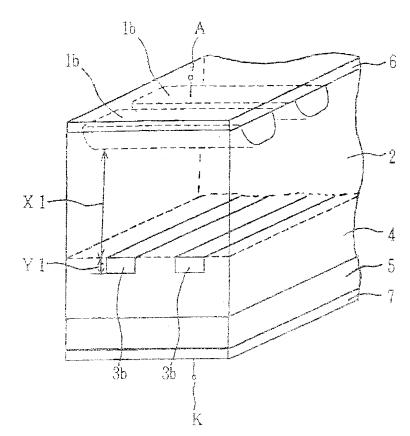




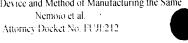
A

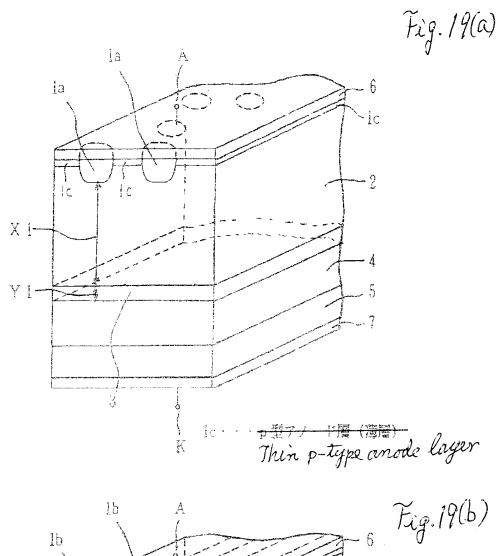
15

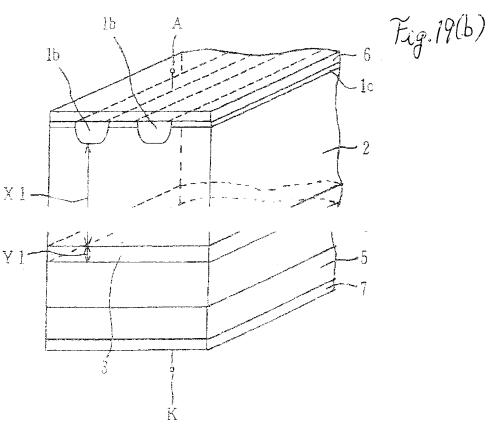
1b

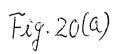


٠.









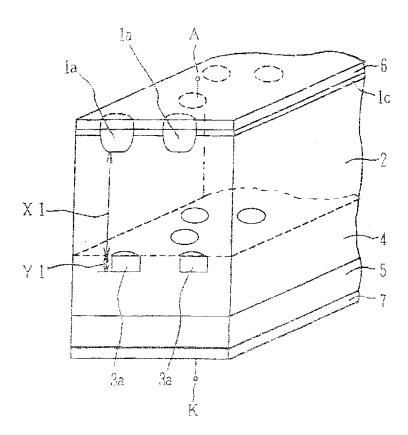
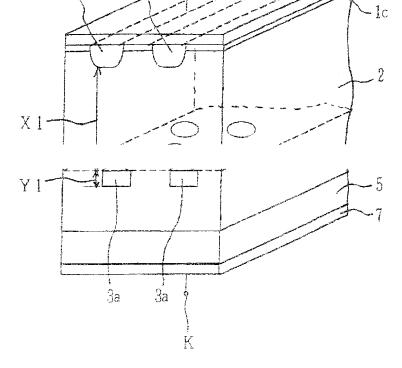


Fig. 20(b)



16

16

1a

X 1-

Y 17

12

7 35 7 3b

O LANGE



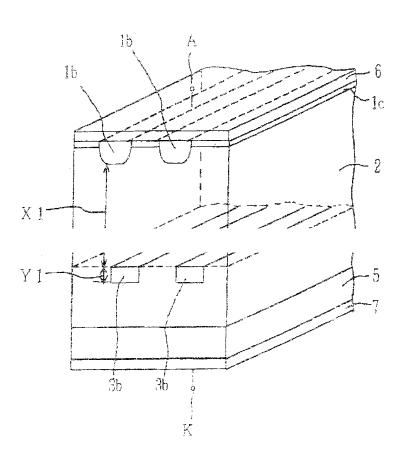


Fig.22

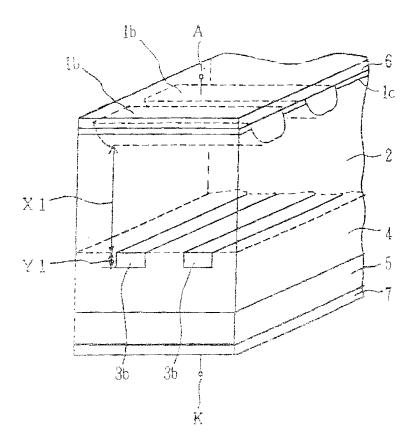
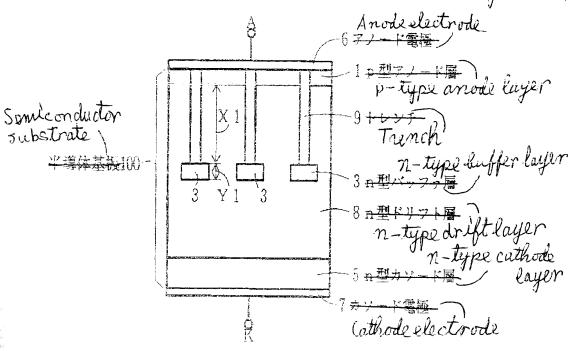
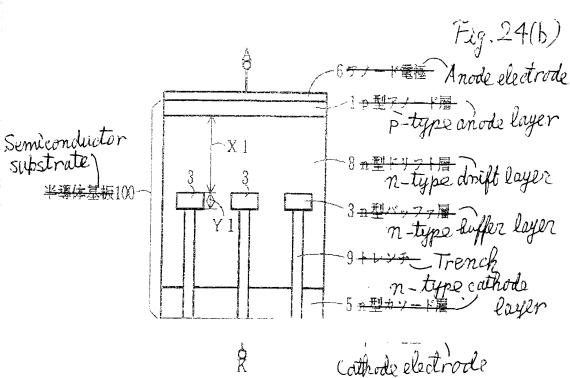
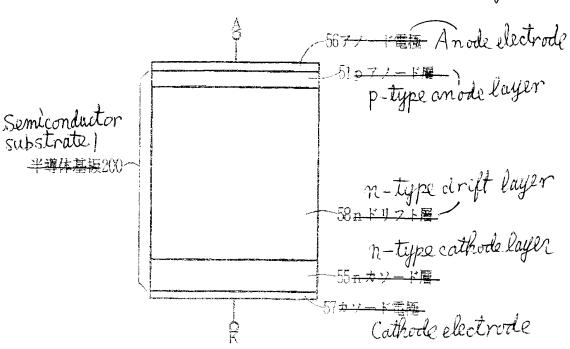
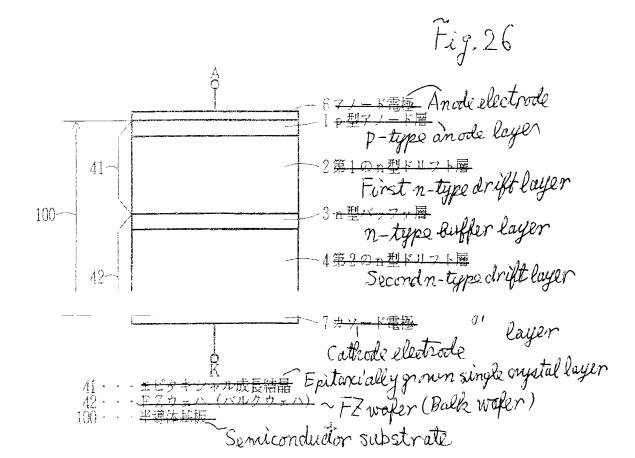


Fig. 24(a)

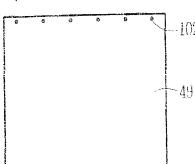








In implantation



-102n型不純物 n-type impurity

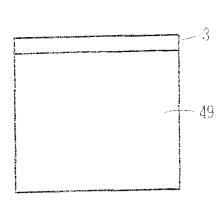
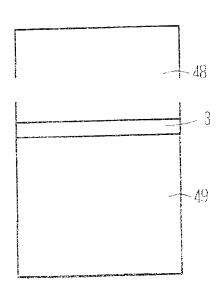
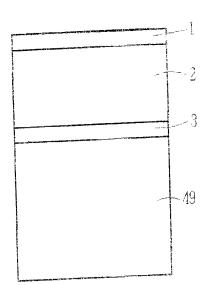


Fig-28





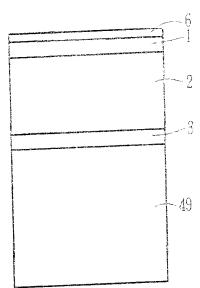
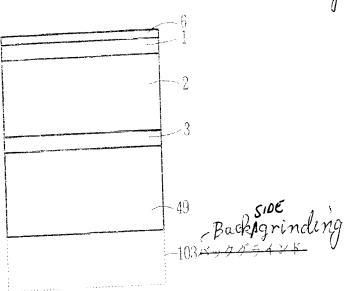
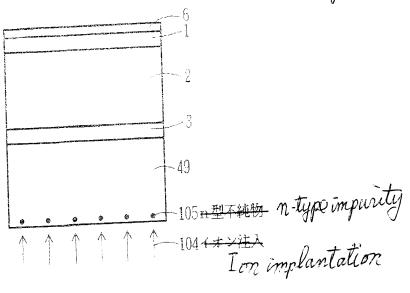


Fig. 32





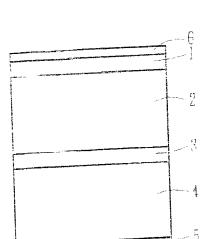


Fig. 34

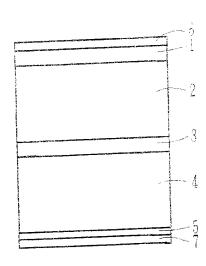


Fig. 35